Work (Name, Fu	ted on: inction)	James P. Yakura, Reliability Engineer																									
	_	23-Sep-19		Form provided by 2700 - Resisten 3.1 - De	senter 2010																						
PCN no	_	19_0197 James P. Yakura																									Ì
For integrated of discrete semico		AEC-Q100 Revision H						in	icludes integ	grated	MATE circu	RIAL P	ERFORM	ANCE 1	EST RE	SULTS (o	n the ba	sis of A	EC-Q100	Revisi	on H) evices,	ogic di	vices,		additi	onal to AEC Q10x	
nele	ect below	=	l			3			П	T	П	П	П	П	ana	og devic	<u>()</u>	T	П	Ш	П	Ť	П	Т			
						Behution loss ArBid			To.			Н	organit de	Ш	Ш	Ш	Ш	Ш	Н	Ш	П	Ш	Ш				
	1					_			0108010		1	4	eto, sec	Ш	Ш				Н	Ш	113	П	Ш		-	1	
		Assessment of impact on Supply Chain regarding following aspec - contractual agreements - technical interface of processability/manufacturability of customer	Remainis risks or Supply Chain?				Further applicable conditions	1	unice) is a	No one of the	Mark Catho	un Storget	an Plans		ra ca		Kito		dasp a Model	Russen 20	ic Ourquits hanchetrate	tor Yes	Ш	Vijeor	макоми		Remarks
Markchange with an "X"		- form, fit, function, quality performance, reliability	Chais?	Understanding of semiconductors experts	Examples to explain	404		Hool	8 20 20 20 20 20 20 20 20 20 20 20 20 20	diction of	over here	Un Temporal	aty trema	The Block Sh	design by by a cal Circu	ke tronigasi	d Carletty	and seem	Mc book Dis baged Desi	MC Pical Dis-	het Circuit	eat the	echage Drup of Torque	tonat Water	Total Sel		
		Type of change				Application have from decaded the minimal for the		controlled by correction	100		- 1			Ħ	5 6 1	Ħ								0 2		201	
1		AMY	P P			2807		AEC.O								5 00 01 0											
Ē	IMAN-02	ong stangap ana migasa an agunus sigan samansas aganomens. Ang shangar alih ingasil an prosmoudellig/manufashundellig al coakenne, ahlah la mal coamanil i Dan malita balaw.	p p	Any change which is not summed in the makin before, but this assertance of authorse in recommended.		0																					
ı	IMD8:01	DANA EMBET Overge of delastered parameters blend to all specification (rein, from App., values) and/or ACDC operational on.	РР	Update of data sheet because of instrinct sharing of the product.	e g. museumentations for pull-apipul steam o NC pine, MS.	. A				- -		T-		1-1-		1-1-1	- - -	1-1-	- -	- - -		- [-]-	1-1-	- -	-	-	
-	IM-DIS-DO	Correction of titals wheel / mode	I P	No instraind stange of the product, only committee in description (secretary, sharing) (b) In case of editorial stranges. (F) In case of expand on product integrity.	(b) ng sarenian al type (P) ng dalahani sarenian ianawa al tea ribonalan alawi sareparani inhaha													. [.].				- - -					
			Ħ	Oraniples of a new neignesis of posterior products or posterior of a new neignesis of the posterior products of the posterior						\dagger	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	T			
	IMERIO	Equalization of additional parameters.	I P	(b) Defection of one parameter which was not documented before. (P) Not known as single change. Only in combination with other changes.	(b) mg, adding new leaded parameter.	A		1		- -							- - -	- - -			- -	- - -			-	•	
•		DEBON	Ħ							Ť		Ħ	Ħ	Ħ	П	П	Ħ	Ħ			Ħ	Ħ	Ħ	T			
ŀ	IME#I01	Geologic shanges in address elements.)	PP	Any director retirected absorgers in design I layed elements with effect on data where! *) Medi included: Untilization in adjust product parameter within specified process wholes and design rules.	e.g. shange of EEC structure e.g. sold / revenue a translatur in lapsal	A	Plane shesh fidda sheet is affected(IEM GE 01)	٠.		1	• "		• D,			- D I	0 0	D .				1	г.	- -		٠	
Į.	IMCE 02	Sensign obsenges in making ()	p p	Any shange of airing belianess elements in ship design I layed with effect on data sheet. ") Not included: Biolifection is adjust product parameter within	ng mak shanga inmial fa lar samalar adan lagad ar esteroi W	c	As Impact on EMC inharity surved by multished i reclaims on surgement invol. As Empact on studying function is not excluded on		, .	Ţ.	A N		П.	H.		Ш	1.	11.	[.]		. .	Ħ.					
- 1	_		H	Non-manager Madihation is adjust product parameter within specified design rules. District of action area.			compound inci. Place should fidde shoul is effected \$250.02.00; Place should fidde shoul is effected \$250.02.00; Place should fisherpe in present instructor(\$226.P4.00)			1	H	H		H	Ш	Ш	H.	\mathbb{H}	Н	Ш	\blacksquare	\parallel	\mathbb{H}	\parallel			
- #	IMCE-03	On shoot ¹)	PP) National states are provided to the	Typinal wheels of the	^	is also allocated. In seaso of Cu stire product please consider AEC 0006.		٠ .		- M	1	• D,			1	11	+			•		Н			•	
ŀ	IMOROL	Province meditation	ı	defined by supplie. (i) Firmmer modification or update without effect of functional performance at the continue from the	(i) mg addition of Fernance approhenisms (P) mg hag for with impact on bendered performance	A								- -			-[.]	. [.].					- -				
- 1		PROCESS - WAVER PRODUCTION	Щ	(F) France militation or update with often of landarid performance of the nationer.						1	Ц	Ц	Щ	Ш	Ш	Ш	Ц	Ш	Ц	Ш	Ш	Ц	Ш	Ц			
F	IMPW01	New (sharge of sofer substante material	РР	New safer malerial.	ng differed suder malerial in surerily release malerial (the sharpe from EPI malerial into n EPI malerial)	c	In seaso of Cu stire product please consider AEC 0006.			I							H	П	-			I	-	T		٠	Qualification effect are, ASC Q150; new diffusion/deping
ŀ	IMPW-00	New water-danseler	PP	Change of sader discrete resulting in equipme and process changes.		c	ingani or sharipts in EEM PNOS and at EEM EQ EL	٠.		ŀ	E N	Ŀ.		EΕ		Ш	- - -		E 1			1	H	- -		•	AEC. Q100. We broad changes that involve multiple abbitules (e.g., vile, realmink, processes), other is wellow AE 2 of this appends and sendors 2.2 of Q100, which allows to the settlement arend usage lead within a to unsee all the provider promodelisms."
	IMPW 00	New load sader thickness.	РР	Change in final scales Hickorea.	n g. shange in Brai shipide Biskness.	c	As Ethermal constanting in allevied (the MODET), ICES, BCS postupe, standard days,) As Engaged on EMC on EEO behavior consult for evaluated.				E N			ε ε			. . .		ε :			. . -			-		
	IMPN OL	Ourse of destrictly aster destrolynatistics denses	p p	Change in electrically assure deping? implantal electronic resulting in a new technology.		A	excluded on companied lead. In case of Cu stre product phase consider AEC 0006.			+	- N			1.			. 	. 				. 		+			
	IMPW 05	Overge of galar malerial indentities	P P			Α.					• N						+	$-\!$	\perp						-	•	
-	IMPW 06	New I sharpe of hadride operation (pinking I redulisation)	РР	Change of indices layer of the Jintimers die an inadicate; Darrie in process, malerial, or discessions reservancy. Alternative see IEEE/PU/III	e.g. shange from Collection to Collecting	c	As Ethermal constanting in allevied (the MOSPET; IOSE, BIGS providings, which and allevier. BIGS program on EMC on ESIO behavior carroll for multiplied. analysis for commonwell land.				. N	٠.					- -	s	ш.			н		н -			ASIQ-Q100. Applicable in all senset proses devices.
	MPW07	New Cohange of metallization / visa / contacts	РР	Change in metallization of bondpash, malerial, layer findeness specifically be ship freeholds as followed forces	e g shange from ASICu in ACu e g shange in over pad metallization	c	In same of Cu so're product please consider AEC Q006.							١.		1.				١.		. . .	1.		-		
×	IMPW OR	New / sharige of pensionless or die enaling (willoud have det)	p p	Owner of top layer on the (belower midd compound and the)	e g addison's polytoide	c	Change of intrinsis menhanisal simus might influence electric families. In sense of Cur sine product please consider AEC 0006.				• M		#,N D,		- -				•			-		- -	-	•	
-	IMPW 00	Overge is proven instructing (σ , growns sharpes like libegraphy, with, unite deposition, difficults, the hash notice preparation-hashpiral,)	- P	(-) If the shange is present indusing sizes, influence the integrity of the first product. (P) If the shange is present indusing un- refluence the integrity of the first product.	(-) ng shange han satis dy eloling ng shange live boliselid is seliad usen l edilalim (P) ng shange of lape titulowas		Pleane also sheek sharges, described und EQUPSENT . Pleane sheek if sharge is described by specific type of shar in this matrix.											. [.].				- - -					Qualification effect depends on type of strange.
•			Ħ							\dagger	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	Ħ	T			
	IMPW IS	Process Hingly kining with specifiation	- P	Votation with powers specification (-): Through with powers specification stem- nal informer the integrity of the lead product. (P): I remaining this on product specification is articipated.	(i-) ng promu sorbid	c	Plane shesh FLATA INSET is effected. Plane shesh ESM PW 00 is effected.	1		- -							- - -	- - -				- - -			-	•	
	IMPN II	Ocean of safer scarder.		(-) I se remaining this is supply shado solid (F) I be shaper of solid specific service shape	(-) mg shange of eather negative with name material composition. mg name material composition and does not	c	Not on component, leaded on level structure (typical for IC). Internation on component level for alreader components.																				Outditeation for C.S. p. Carboline difficult on product lead. Outstainteation on make tend only on lead schoolers. IECC 2000: The board changes find insolar multiple distributes jn q., sile, mulmink, processess, since is written in 2 or less appeared and unation 2.3 of COSS which allows for the schoolers of more cases less of schoolers in some all the procession.
			Ц	(F) If the shange of notice cappiler can influent the integrity of the final product.	water compression and does not be a same maintain instructor. (P) my new supplier with impact on substrain material and / or strainfold behavior.		equeled. In same of SCI subsisted HP properties have to be qualified. Please when A SEM PW OI and SEM CE 61 is affected.								Ш	Ш	Ш	Ш			Ш	Ш	Ш				promounts), while is writine A1.2 of this approxime and unitine 2.3 of C(III), which allows he time whealies of sured more lend unitides in some all the purchale permutations."
	IMPW ID	Overge of specified subspecses sequence (delation and/or additional presents slop)	- Р	Any change which is not comed by another by of change. Nick in to be assessed. (-): He Rick for Engely chain. (P): Fink for Engely chain (reference on produc-	(i.) ng shange of disoring process in suder production (P) ng additional sinter implentation after shandard implentation (to protect sinual again planformus impulses).	c											- - - - -		- - -			-		
t	men o			Maler his humalism with additional shanges.	Interference Impulsers)	A	hand for the sold days and he see for the			. †.	. N			Н.	Ш	Ш	Н.	#					Н.	н.			ASC Q100. The broad sharipes that broader multiple althoubes (e.g., site, multiple), processing, other is worker AS 2 of this appendix and worker AS of Q100, which delays for the worker AS of Q100, which delays for the worker of processing of processing of the pro
			H	(described above). Change in process includes for lifespapitic process and malarial.	List an embarar of defect mask	-				+	H	H		H	H	Н	H	$^{+1}$	H	\mathbb{H}	+	H	+		H		alman he the selection of sared name lent solicites in some all the parable permutations."
- 1	MPW 16	Shapady	- P	(-) If the sharpe is process, including sizes of following the integrity of the final product. (P) If the sharpe is process, including year of forms the integrity of the final product.	(P) ng shange bun Elinam prosess is En prosess ng shange bun sarkati inis pojestan mak	c	Please also sheek sharges described und EQUPMENT .	•	٠.		• N	٠.					- - •	- - -		•		- - -			-	٠	
Ī	mre	Outer I Medicare Defends		Change in process includes for colds / interior districts process (c). If the change in process, including sizes,			Plant the shell shown to the state of the state of			T			#N ^			Ш						I	Ш				
			Ц	otheres he integrip of the first product. (P) If the sharpe in present industry, can otherwise the integrity of the first product.		Ĺ				I	П	Ц		П	Ш	Ш	11	Ш	Ц	Ш		Ш	Ш				
- #	IM#0-01	New Stad andre Statemen.	PP	Change in final scales biolomes.	Change in final objekte blakenes	A	In sease of Cu stire product please consider AEC QUOS.			Ī	E N		T	EE	П	Ш	ŢĪ.		E 1	H	Ŧ		Ħ	Ţ.		•	
Ŀ	IM#0-03	Since I sharinge of Bresidesh motolisation Since I sharinge of Besidesh motolisation	PP	Change in horolysols, malerial, pad piloh, sorla shangan, layer bishness. Change of listliers layer of the finitumen site an- lassificate). Change in prosons, malerial, or	e g shange from ASICurin ACuring shange in some pad metablastion a g shange in some pad metablastion a g shange from Orbitifia in Orbitifig	Δ .	In seaso of Cur wire product pleaser consider AEC QUOS.	1										- - -								•	
<u> </u>	IMAD OL	Ounge of water sating or number of promisin good date, or mader.	Н.	dimension. Needed information for pink & place massives. (b) amount of providing good days on safes. (b) information washer unique and easier mappin.							H	H	H.				1	11		Ш		Ħ	Ш				
F	-		H	(F) influence on under unique and under mappin Defender of data in under migra region which has the defended described.	ery mg. Information shange for pick it pione mashine. (b) mg. approximate of males subject (number)				_	-	H	H	H	H	H	H	H	H	H	Н	+	H	H	+			
	IMAC-OS	Overge of optical apprehense of earlier edge region (the initie coverage or edge exclusion)	Ľľ	Defenden of den in under nitge region which he defined should bendemakly. (b) in same of maker nitge in affected only. (F) in same of single size in affected. Needed information for samina and with Estim.	instantial square) (P) mg polyinide as new unaling as six	•						Ш	1		Ш	Ш	#	#		Ш		11	Ш			•	
ŀ	MAD OR	De unite or separation	P	Needed information for saming and pick & plan materies (F) If the change is saming process does not otherwise the integrity of the final product. (P) in case I product is delicent on order	(n lape anti-rel) (P) no information sharpe for pith & place reaction. ag information sharpe for path & place		Please should EMM ED bits affected.	٠.							- -		-[-[-	- [-]-							-		
	IMAD-**	Ge Personales / Ones	H.	Change in process includes for the preparation			Plane shed (WMAD Mi) effected									Ш	Ħ	\parallel		Ш		Ħ	Ш	н.			
	_		Ц		(P) ng shange is sinaning procedure after shange of saning equipment.					1	ЦĨ	Ц	Щ	П	Ш	Щ	#	\parallel	Ш	Ш		Ц	Ш	1			
<u> </u>	IMAC OR	Next (sharpe of persivation or directaling	P P		e g. addition of polytoide e.g. shange of polytoide blokness.		In sease of Cur wire product pleaser consider AEC QUOS.	<u> </u>				<u> </u>					11	11				- - -		1	-	•	
ŀ	men.or		p p	Change in dimensions of existing package. New insoftware material in new composition.				1		ŀ	• 10			11.		H	H	H							G	-	
ŀ	ark0		H	Ourge is healthnee dimensions which has been in the property of the contract o	n. g. shange han aloyd I scopper n. g. shange helumon loss different suppor ali		ESD investigations are only necessary if internal ground and			ł		H		H	H	H	H	+	H	H	•	LH	H		4		
- 1	IMPR-00	Overge in lead area dissensions	PP	Ounge in leadings discussions which has input in the specified electrical parameter as data before specification (e.g. beat sirk, pin- directalism, der paide size	e. g. shange in lead home geometry		de Firepail on EMC lefturier navvol he moduleted / modulete de Firepail on EMC lefturier navvol he moduleted / modulet on navopument level. In nazur of Curative product pleaser consider AEC 0000.			•								11			-	L H					
ŀ	IMPRO	Ounge of lead have finishing material / area (internal)	РР	Change of nurbon material of the allock yaed as second bond area (e.g. influence in advantors in mold compound, wedge bond reliability)	e g shange lives Ag Each to 10° production ages e g shange lives Ag upol to An upol e g shange lives Ag upol to An upol	c	In sease of Car stive product please consider AEC QUOS.			. -	- M			- с	• -		- -		-			L H		н -	-	-	For sire band shough last Per. & Pedignames shange comparison in multide powers shange reliables (AECOV).
ŀ	IMPA.OS	Overge of lead and lead stop plating mulerially lating findness (external)	РР	Change in malerial and / or process resulting in new inclinalogy (e.g. pure lin).	ng shange in Intel slag slash ng shange tron In Inte NiPúllu ng shange of layer ibidinana	0				. -	• N			- c	• -		- - -					L H		н -			
F	IMPA OF	Burg Malmid (Weld Byden (plenul)	p p	Dank die or die in substrate (Sp-ring)	n g shange in Philosomalosid n g shange of supper pilan	c	A: Firegani on EMC inharite narred be evaluated / exclude on component level of the alloch-han impact on strategical	1			• N	ŀĪ			H	1-1-1	1-[ΗĪ	H		· L ·	ΗĒ	H		•	
ŀ	IMPILOT	Die allente material	PP	Ownge of the allock material and / or yourses resulting in a new inclinating (n.g. soft solder, agony, etc.)		c	on companient level (If the allian); has impact on electrical conductivity). In seaso of Curative product please consider REC 0200.	•			• N		-	- -			11			-		L H		нн	-	٠	
		Ounge of side bonding					& in see of bond degram sharps and EMC served be evaluated an component level.							Ш			П	П				I	Ш				Parameter Analysis. Untilly required only the Parameterism. In general: Eller and the medical change with impact on handprosons, jo. g. from As to Col. communication.
	IMPILOS		PP	Malarial, diameter, shange in bording diagram and for shange in process, resulting in a new technology.	e g, shange from single in similar board or g, shange from sinch board in skich on hall board.	c	Places also should shargers described under SIM BQ-01 In seas of Car sine bonding places consider AEC-QSSS.	٠,			• 0	1					П			М -		- н			*	٠	AEC (2000 The Install changes that involve multiple abbilishes (e.g., site, materials, powerses), other to excite AEC 31 of this appendix and sention 2.3 of QUID, which address to the servicies of servicious leaves and the provider permutations."
	IMPAGE	Edebular / Interpreser	,	Ownge of BESS substitute	ng shaqan in maling		A logani on EMC tehnolor saved for evaluated i endoded on surgeometricus. Ar Emparium studeloid function is not evaluated on surgeometricus.			Ī.	. ,						1	Ш				. L H		нн			
		-	Ц	Change of BESI substitute			compressed level. In sease of Cur stire product phones consider AEC 0006.				IJ.	Ц		П	П	Ш	Ш	Ш		Ш		Ц	Ш				

SEMPA 10	Sir Dermail Underfill	- 1	Expecting layers for samples packages like if ship and i or sharpe in parameter resulting in a package. (c) it is barger alone and influence the integrity of the load product. (P) it impact on product integrity is articipated.	(i) ng shange of degenering spend (P) ng shange of united material	c				•		м •	• -													- н	-			
MMPA.11	Overgr of mild surprised I recognishes reduced			e.g. shange in grown mald compound e.g. shange of littler parishes		As impact on Demos menhanised climas seasoned by relaxable of mold compound, inflamousmoling inhibitings and social and compound, inflamousmoling inhibitings and social production and supplied programs by these Demos has seasoned and supplied to the product of the seasoned of proching any personnel product in compound could after depart between (p. 4 glight cignal seasoned). In season of December 2 products places unrelater AEC CODE.					м •					•			-				L -				-		
MMPA.12	Change of hermotic sealing	Р	Affected areas are material and process, of Demosits (e.g. securits) pushages, support die and sealed devices (e.g. pressure sersors)	e g stange of wasting material for Field		As impact on EMC instantor cannot be evaluated / evaluated comparent level (F encapsulation / unaling has impact on electrical constantistic).								- - -	• -	• •	- - -	- -	. -				٠.	٠.	٠.	-	-		
SEMPA-IS	Overgred product mattery		Change of marking on device and I or shange process reading in a one leabnings; (b) If shange data satisfactors for integrity of the load product. (F) I impact on product integrity is articipates	(B) a g sharpe of appearance (solitional marking) (P) a g sharpe have intend marking to lase marking a g, marking of yor 1																						,	-		
MINERAL NA	Overgr is present indending (ing searing direction), bending midding pinking bire and bern, had better preparation,)	- 1	(-) If the sharge is present including date. Post the sharge is present including date. (F) If the sharge is present including van reformed the integrity of the final posturi.	(P) mg shange bon hallbond is sibde		Please also should shargen described under SIM-80-01. Please should inharge in described by specific type of share in this matter.	٠.		-					- - -												-			
MMPA.IS	Process ideglip keing silbis spesilastus.	-	Validios within process speculication (i.i): Fluring within process specification does post influence the integrity of the final product. (P): Emparican product speculication is entispated.	(-) ng promu sorbal	o				- 1																	-	-		
00MPH-10	Change of detect material supplier	-	Change of suppliers for silvest materials which sound in accountly promone (ECAS). (b) I shange does not influence the integrity of the final product. (P) I impact on product integrity is artisty-does	P) ng shange la neu mulii sampunni napi ng sakilansi kesilana supilar sah specila kesilana mandadaing kelinology		Please should entirely be sharped																					-		line shange of malerial.
MMPA.17	Overge of specific-financially process sequence (station and/or additional/process slap)	- 1	(-) no influence in final product integrity or provided sequence (P) influence in final product integrity separate sequence	(i) ng additional description ng deletion of optical impension (P) ng shange lead brinking precision & have peak tion & form	a											- - -		. -									-	6	Socillasion deprode or openila charge.
SEMPA IS	More of all or part of assembly in a different headen-historisation-hander.	۵	P decembly transfer or releasation	e.g. dad source/ life shalegy	c	A or B: impact on other type of changes described under PROCESS ASSESSED with SSM 8Q-04. In same of Coroling product places consider AEC-Q006.	•		•		м -			- -	• т	•				- •			L H		н	u	٠		White best have in he store or mustiving heard MC-Q100. The broad sharges that broads multiple attributes (e.g., sile, materials summans, othe is multim A1 3 of this approxise and motion 2.3 of Q100, which there is the relation of more insert and whiches in more all the possible semination.
MMPA.10	the units or expansion	-	Expansion prosess hom single scales in den. (-): The sharpe in prosess does not influence the integrity of the final prosion. (P): Emparicus position integrity is artistyales.	e(i) ng shange af berluishi. (P) ng shange ban saningle lawr sal	c				•		м -			- -													-		
MMP4.20	Sir Perpendin / Chan		Owngo is present individual for six preparate classing (i): If the sharpe is present class and influence the integrity of the final position. (P): If impact on position integrity is articipated.		c					•	м -	•													н -		-		
MMPA.21	Midding (Emapsubline practice)	- 1	Change is present individual for molding / emapsolution. P. (-): If the sharpe in present does not influence the integrity of the first product. (P): If impact on product integrity is articipates.	nj. j. ng hring ultin pasana upasilsalan i	c				•		м •	•			• -	• -		. -					L -			-	-		
BMPLO:	PACKING SHIPPING PASING SHIPPING SHIPPI	Р	P Pastingshipping specification change.						-	-1-1	- -			1-1-	1-1-1	-1-1-	1-1-	1-1	1 -		- -	- 1-			- -				
SEMPLO	Dry pasit requirements sharque Change of santon (top, cost)		Change of day peak requirements (e.g. shange MES) Change of sames (e.g., see)							- -	- -							-								-	-		
MMPE OF	Compart lateling		Change it have you, may Change of initialing also on sed. (g): Change of male laid without impact on P knowle. (F): Changes of male laid initial information who effects did a promoting of custome.	(B) ng additional information (NoVII stamp) (B) ng shange of defined nonemblakes for de decommuning														П									•		
EMEGE!	Production from a new equipment lead which wars a different hasta tendrology which due he to	р	Dange in present includes which is solution or and also	Overge box single scales in halob process (e.) over pad metalization (e. g. dembar scaling (mechanical in laser scalin	A					П	Т	П	П	Π	П	П	П	П	Т	П	П	П	Т	Т	Т	П		T	Mended arrowns charger in in obesis.
MMAGE	unique hom or function can be expected to influence the integrity of the find product	-			^									П	Ш	- 1	Ш	П	Ľ	Ш			1	1					process process condige in its classic.
MMAGE	Profesion has a sea equipme that which was the same has in inviving popularized equipment or solvening straining equipment profflows drawing or process.		POX required for destinated engineers for sensitive compared production. (i) Enhance does not influence the integrity of the lead product. (P) Emparical product integrity is articipated.	(i) p. a.g. maleration of ministry equipment post (EP) a.g. maleration of destinate a equipment in cases havin imbrasings sill need in the proven	c c																						•		
MM4013	Change is find and equipment type that own a different trademings. TEXT FLOW	P	Dungs of leater (only in name of laster der final lead means under lead.)	er g shange insier equipment from LTX to Tenselpre	c			·	-	- -	- -		- -	H	- -	- -	Ш	H	-		- -	- -	ŀ	- -	-		٠		Sup REF. dela sersialus
BBM 75-01	Since of all or year of electrical mades benkensive final lend in a different incultive/silventrack	Р	P Tende transfer or relimation Check impact on SEMANCO	Dual source situlegy	с		•			- -					<u> </u>		11		Ŀ	٠.		- [-		-[-		-	•		Tage 1937, dela corolation
	gean gean	Ŧ	T	1					f	Ħ	ī	ī	Ħ	ī		T	ī	Ħ	ī	ī		ī	ī	T					
MMQS41	Change of the test assembly the second test and by the supplie to make data should complicate by a distribution of distributed assembly the block of established assembly of makeing procedure or sampling).	-	e qui est fina kindi, melastino humilinen integradare memanemento in lam integradare memanemento, shange in hamini dan in memane. (a) E though dans sui inhamon itse integrity o the land product. (b) E impant on product integrity is articipales	(-) is go had implemented without audience regularization. The implementation (b) is go and administration from temperature pressurements for law impressurements resourcements. In law impressurements and subsequents in form in pressure.	c			-																			٠		rounnelse Andynis, Enlis vandalien Per [*] ann in [*] skangen, EUE musemmenled
	Tests, which should be considered for the appropriate process ch				C					-								-										_	
	rests, which should be considered for the appropriate process cha	inge.			С		•	-	٠	• •															- -	-	•		
	Tests, which should be considered for the appropriate process ch	ingo afti	or selection of condition table.						•	•	м -	• 10	D,J •	•					•	٠.	•					-	٠		
	Suppliers performed tests (mark with an ${\mathbb X}$ for done or ${\mathbb V}$ for gen	eric)												П		П	П												
	Reason for exception of tests and/or usage of generic data:																												

Not required.
 Information Note required.
 P PCN required.

And the state of t